











CSD17571Q2

SLPS393A - OCTOBER 2013-REVISED JANUARY 2015

CSD17571Q2 30V N-Channel NexFET™ Power MOSFETs

Features

- Low Q_a and Q_{ad}
- Low Thermal Resistance
- Avalanche Rated
- Pb-Free Terminal Plating
- **RoHS Compliant**
- Halogen Free
- SON 2 mm × 2 mm Plastic Package

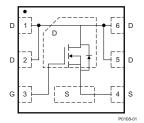
Applications

- Optimized for Load Switch Applications
- Storage, Tablets, and Handheld Devices
- Optimized for Control FET Applications

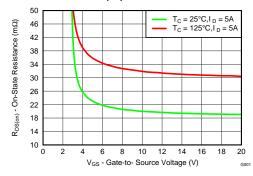
3 Description

This 30 V, 20 mΩ, SON 2×2 NexFET™ power MOSFET is designed to minimize losses in power conversion and load management applications, while offering excellent thermal performance for the size of the package.









Product Summary

T _A = 25°	С	TYPICAL VA	LUE	UNIT
V_{DS}	Drain-to-Source Voltage	30	V	
Q_g	Gate Charge Total (4.5 V)	2.4	nC	
Q_{gd}	Gate Charge Gate-to-Drain	0.6		nC
В	Drain-to-Source On-Resistance	V _{GS} = 4.5 V	24	mΩ
R _{DS(on)}	Drain-to-Source On-Resistance	V _{GS} = 10 V 20		mΩ
V _{GS(th)}	Threshold Voltage	1.6		V

Ordering Information⁽¹⁾

Device	Media	Qty	Package	Ship	
CSD17571Q2	7-Inch Reel	3000	SON 2 x 2 mm Plastic Package	Tape and Reel	

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Absolute Maximum Ratings

	Absolute Maximum Natings									
T _A = 2	5°C	VALUE	UNIT							
V_{DS}	Drain-to-Source Voltage	30	V							
V_{GS}	Gate-to-Source Voltage	±20	V							
	Continuous Drain Current (Package Limit)	22	Α							
I _D	Continuous Drain Current ⁽¹⁾	7.6	Α							
I_{DM}	Pulsed Drain Current, T _A = 25°C ⁽²⁾	39	Α							
P_D	Power Dissipation ⁽¹⁾	2.5	W							
T _J , T _{stg}	Operating Junction and Storage Temperature Range	-55 to 150	ů							
E _{AS}	Avalanche Energy, single pulse I_D = 12 A, L = 0.1 mH, R_G = 25 Ω	7.2	mJ							

- (1) $R_{\theta JA} = 50$ on 1 in² Cu (2 oz.) on 0.060" thick FR4 PCB
- (2) Pulse duration 10 µs, duty cycle ≤2%

Gate Charge

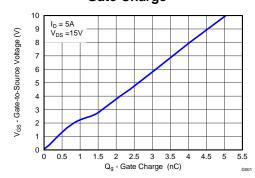




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4 Revision History

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5 Specifications

5.1 Electrical Characteristics

 $T_{\Delta} = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
STATIC	CHARACTERISTICS		•		•		
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30				
I _{DSS}	Drain-to-Source Leakage Current	V _{GS} = 0 V, V _{DS} = 24 V			1	μΑ	
I _{GSS}	Gate-to-Source Leakage Current	V _{DS} = 0 V, V _{GS} = 20 V			100	nA	
$V_{GS(th)}$	Gate-to-Source Threshold Voltage	$V_{DS} = V_{GS}$, $I_{DS} = 250 \mu A$	1.3	1.6	2	V	
р	Drain-to-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{DS} = 5 \text{ A}$		24	29	mΩ	
R _{DS(on)}	Drain-to-Source On-Resistance	V _{GS} = 10 V, I _{DS} = 5 A		20	24	mΩ	
g_{fs}	Transconductance	V _{DS} = 15 V, I _{DS} = 5 A		43		S	
DYNAMI	IC CHARACTERISTICS		·				
C _{ISS}	Input Capacitance			360	468	pF	
C _{OSS}	Output Capacitance	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz		101	131	pF	
C _{RSS}	Reverse Transfer Capacitance			9	12	pF	
R _g	Series Gate Resistance			3.8	7.6	Ω	
Qg	Gate Charge Total (4.5 V)			2.4	3.1	nC	
Q _{gd}	Gate Charge – Gate-to-Drain			0.6		nC	
Q _{gs}	Gate Charge Gate-to-Source			0.9		nC	
Q _{g(th)}	Gate Charge at V _{th}			0.6		nC	
Q _{OSS}	Output Charge	V _{DS} = 15 V, V _{GS} = 0 V		3.4		nC	
t _{d(on)}	Turn On Delay Time			5.3		ns	
t _r	Rise Time	V _{DS} = 15 V, V _{GS} = 4.5 V, I _{DS} = 5 A		19		ns	
t _{d(off)}	Turn Off Delay Time			8		ns	
t_f	Fall Time			2.6		ns	
DIODE C	CHARACTERISTICS						
V _{SD}	Diode Forward Voltage	I _{DS} = 5 A, V _{GS} = 0 V		0.8	1	V	
Q _{rr}	Reverse Recovery Charge	V 45 V L 5 A di/d+ 200 A/··-		2.3		nC	
t _{rr}	Reverse Recovery Time	$V_{DD} = 15 \text{ V}, I_F = 5 \text{ A}, di/dt = 300 \text{ A/}\mu\text{s}$		11		ns	

5.2 Thermal Information

 $T_A = 25$ °C unless otherwise specified

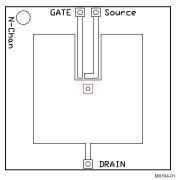
	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance (1)			6.2	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance (1)(2)			65	C/VV

⁽¹⁾ R_{θ,JC} is determined with the device mounted on a 1 inch² (6.45 cm²), 2 oz. (0.071 mm thick) Cu pad on a 1.5 inches x 1.5 inches (3.81 cm x 3.81 cm), 0.06 inch (1.52 mm) thick FR4 PCB. R_{θ,JC} is specified by design, whereas R_{θ,JA} is determined by the user's board design.

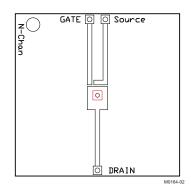
(2) Device mounted on FR4 material with 1 inch² (6.45 cm²), 2 oz. (0.071 mm thick) Cu.

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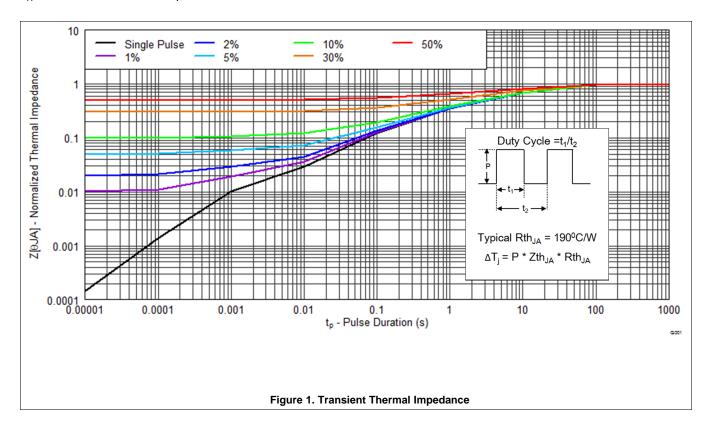
Max $R_{\theta JA} = 65$ when mounted on 1 inch² (6.45 cm²) of 2 oz. (0.071 mm thick) Cu.



Max $R_{\theta JA} = 235$ when mounted on minimum pad area of 2 oz. (0.071 mm thick) Cu.

5.3 Typical MOSFET Characteristics

T_A = 25°C unless otherwise specified



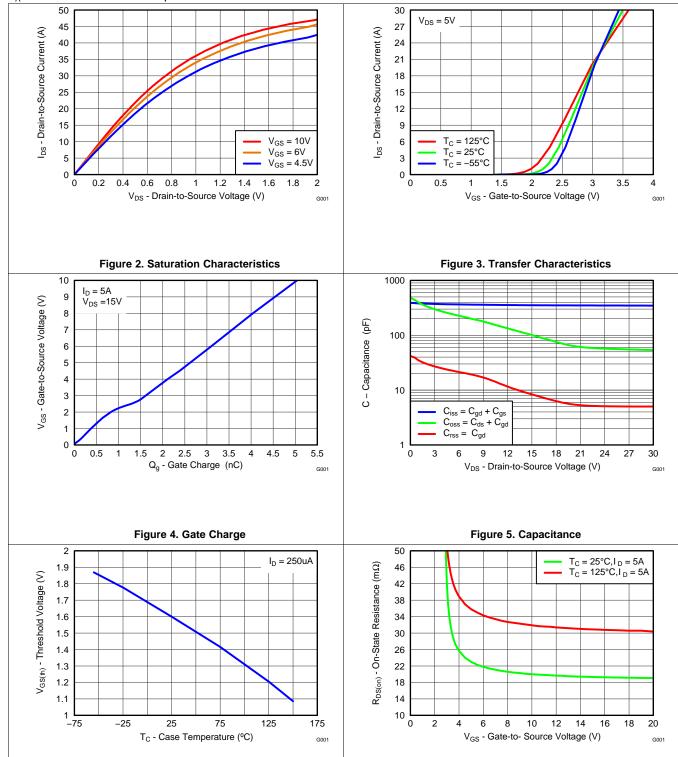
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Typical MOSFET Characteristics (continued)

 $T_A = 25$ °C unless otherwise specified



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Figure 6. Threshold Voltage vs Temperature

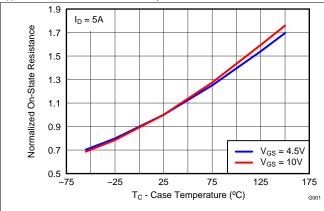
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Figure 7. On-State Resistance vs Gate-to-Source Voltage



Typical MOSFET Characteristics (continued)

 $T_A = 25$ °C unless otherwise specified



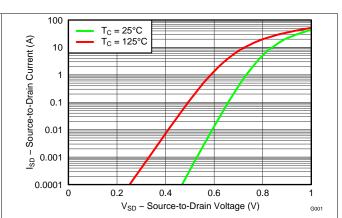
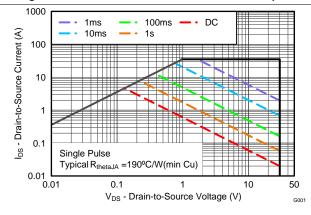


Figure 8. Normalized On-State Resistance vs Temperature





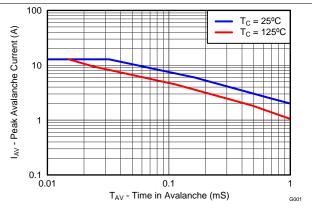


Figure 10. Maximum Safe Operating Area



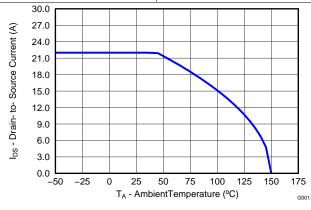


Figure 12. Maximum Drain Current vs Temperature



6 Device and Documentation Support

6.1 Trademarks

NexFET is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

6.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

6.3 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

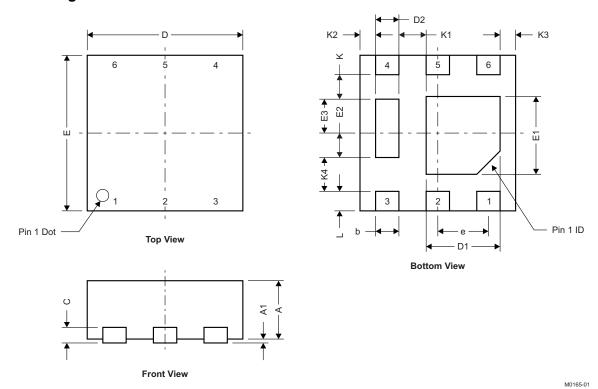
Product Folder Links: CSD17571Q2



7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

7.1 Q2 Package Dimensions

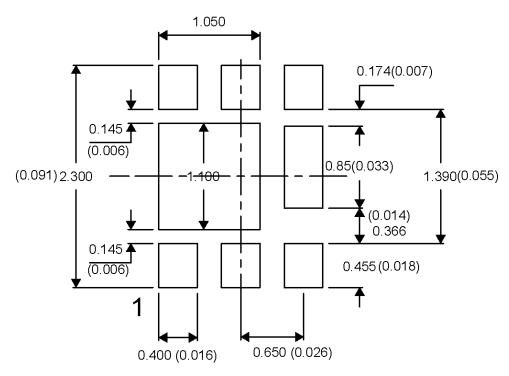


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DIM		MILLIMETERS INCHES						
	MIN	NOM	MAX	MIN	NOM	MAX		
Α	0.700	0.750	0.800	0.028	0.030	0.032		
A1	0.000		0.050	0.000		0.002		
b	0.250	0.300	0.350	0.010	0.012	0.014		
С		0.203 TYP			0.008 TYP			
D		2.000 TYP			0.080 TYP			
D1	0.900	0.950	1.000	0.036	0.038	0.040		
D2		0.300 TYP			0.012 TYP			
E		2.000 TYP			0.080 TYP			
E1	0.900	1.000	1.100	0.036	0.040	0.044		
E2		0.280 TYP			0.0112 TYP			
E3		0.470 TYP			0.0188 TYP			
е		0.650 BSC			0.026 TYP			
K		0.280 TYP			0.0112 TYP			
K1		0.350 TYP			0.014 TYP			
K2		0.200 TYP			0.008 TYP			
K3		0.200 TYP			0.008 TYP			
K4		0.470 TYP			0.0188 TYP			
L	0.200	0.25	0.300	0.008	0.010	0.012		

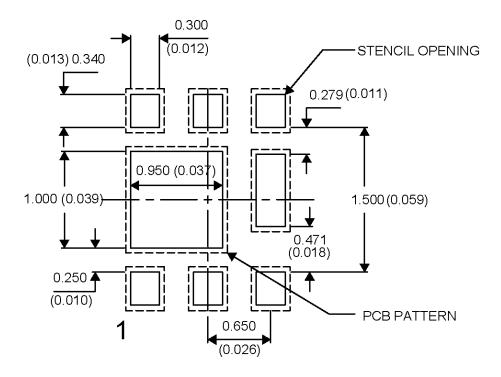


7.1.1 Recommended PCB Pattern



For recommended circuit layout for PCB designs, see application note SLPA005 - Reducing Ringing Through PCB Layout Techniques.

7.1.2 Recommended Stencil Pattern

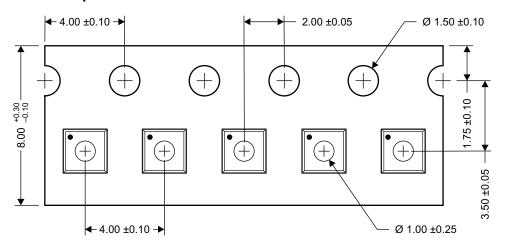


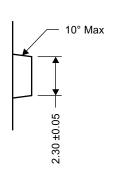
Product Folder Links: CSD17571Q2

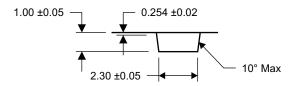
All dimensions are in mm, unless otherwise specified. Note:



7.2 Q2 Tape and Reel Information







M0168-01

Notes: 1. Measured from centerline of sprocket hole to centerline of pocket

- 2. Cumulative tolerance of 10 sprocket holes is ±0.20
- 3. Other material available
- 4. Typical SR of form tape Max 109 OHM/SQ
- 5. All dimensions are in mm, unless otherwise specified.



PACKAGE OPTION ADDENDUM

6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CSD17571Q2	ACTIVE	WSON	DQK	6	3000	Green (RoHS & no Sb/Br)	NIPDAU SN	Level-1-260C-UNLIM	-55 to 150	1751	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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